

 INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Docket: 1011-57087		App: 09/385,666	
				Applicant: Suaya and Gabillet			
				Filed: August 26, 1999		Art Unit: 2858	
U.S. PATENT DOCUMENTS							
Init.*		Number	Date	Name	Class	Sub	Filed
T.P.		5,999,010	12-7-99	Arora et al.	324	765	
FOREIGN PATENT DOCUMENTS							
		Number	Date	Country	Class	Sub	
OTHER DOCUMENTS							
T.P.			McGaughy et al., "A Simple Method for On-Chip, Sub-Femto Farad Interconnect Capacitance Measurement", IEEE Electron Device Letters, Vol. 18. No. 1, January 1997				
EXAMINER: Thai Phan				DATE 11/02/02			
*Examiner: Initial if considered, whether or not in conformance with MPEP 609; draw line through cite if not in conformance and not considered. Send copy.							

